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What is claimed is:

A method of constructing a probe assembly, comprising the steps of:

creating a layout of a flexible circuit and etching said layout on said flexible circuit, wherein said layout results in a pattern of unetched portions;

drilling plurality of holes in a pair of rigid PC Boards in a pattern matching the pattern of unetched portions;

plating the plurality of holes with annular rings;

making a laminate stack by laminating the flexible circuit between the two PC Boards;

pressing a plurality of nail pins into the laminate stack, wherein each of said nail pins has a head and each of said pins is pressed until the head is flush with one of said PC Boards and said pins extend through said laminate stack;

placing solder preforms over the portion of said pins extending through said stack; and

reflowing said solder preforms to mechanically and electrically attach the pins to one of said PC Boards.

- The method of claim 1, further comprising the step of:
 attaching a BGA socket to said laminate stack so that the ball grid array of said

 BGA socket contacts with the heads of the plurality of pins.
- 3. The method of claim 1, wherein said flexible circuit contains a plurality of inner signal layers, each of said layers having said pattern of unetched portions.

- 4. The method of claim 3, wherein each of said unetched portions is a star pattern.
- 5. The method of claim 4, wherein each of said unetched portions has a diameter slightly larger than a diameter of a nail head pin.
 - 6. The method of claim 5, wherein the plurality of holes drilled into the pair of rigid PC Boards have diameters equal to the press fit diameter of the nail pins.

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